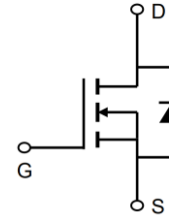


30V N-Channel Enhancement Mode MOSFET

Description

The AP180N03P/T uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.



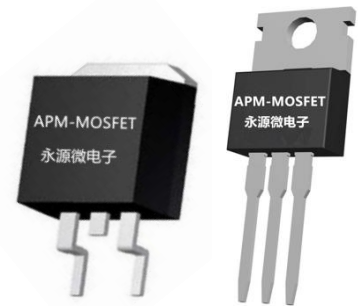
General Features

$V_{DS} = 30V$ $I_D = 180A$

$R_{DS(ON)} < 2.8m\Omega @ V_{GS}=10V$

Application

- Battery protection
- Load switch
- Uninterruptible power supply



Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|------------|-----------|--------------------|----------|
| AP180N03P | TO-220-3L | AP180N03P XXX YYYY | 1000 |
| AP180N03T | TO-263-3L | AP180N03T XXX YYYY | 1000 |

Absolute Maximum Ratings (TC=25°C unless otherwise specified)

| Symbol | Parameter | Rating | Units |
|-------------------------|--|------------|-------|
| V_{DS} | Drain-Source Voltage | 30 | V |
| V_{GS} | Gate-Source Voltage | ± 20 | V |
| $I_D @ T_C=25^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V^{1,6}$ | 180 | A |
| $I_D @ T_C=100^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V^{1,6}$ | 145 | A |
| I_{DM} | Pulsed Drain Current ² | 500 | A |
| EAS | Single Pulse Avalanche Energy ³ | 246 | mJ |
| I_{AS} | Avalanche Current | 70.2 | A |
| $P_D @ T_C=25^\circ C$ | Total Power Dissipation ⁴ | 187 | W |
| T_{STG} | Storage Temperature Range | -55 to 175 | °C |
| T_J | Operating Junction Temperature Range | -55 to 175 | °C |
| $R_{\theta JA}$ | Thermal Resistance Junction-Ambient ¹ | 62 | °C/W |
| $R_{\theta JC}$ | Thermal Resistance Junction-Case ¹ | 0.8 | °C/W |

30V N-Channel Enhancement Mode MOSFET

Electrical Characteristics (at $T_J=25^\circ\text{C}$ unless otherwise specified)

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|------------------------------|--|--|------|-------|-----------|----------------------|
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{GS}=0V, I_D=250\mu A$ | 30 | --- | --- | V |
| $\Delta BV_{DSS}/\Delta T_J$ | BV_{DSS} Temperature Coefficient | Reference to 25°C , $I_D=1\text{mA}$ | --- | 0.014 | --- | $V/^\circ\text{C}$ |
| $R_{DS(ON)}$ | Static Drain-Source On-Resistance ² | $V_{GS}=10V, I_D=30A$ | --- | 2 | 2.8 | m Ω |
| | | $V_{GS}=4.5V, I_D=15A$ | --- | 2.6 | 3.5 | |
| $V_{GS(th)}$ | Gate Threshold Voltage | | 1.2 | --- | 2.5 | V |
| $\Delta V_{GS(th)}$ | $V_{GS(th)}$ Temperature Coefficient | $V_{GS}=V_{DS}, I_D=250\mu A$ | --- | -4 | --- | mV/ $^\circ\text{C}$ |
| I_{DSS} | Drain-Source Leakage Current | $V_{DS}=24V, V_{GS}=0V, T_J=25^\circ\text{C}$ | --- | --- | 1 | uA |
| | | $V_{DS}=24V, V_{GS}=0V, T_J=55^\circ\text{C}$ | --- | --- | 5 | |
| I_{GSS} | Gate-Source Leakage Current | $V_{GS}=\pm 20V, V_{DS}=0V$ | --- | --- | ± 100 | nA |
| g_{fs} | Forward Transconductance | $V_{DS}=5V, I_D=30A$ | --- | 50 | --- | S |
| R_g | Gate Resistance | $V_{DS}=0V, V_{GS}=0V, f=1\text{MHz}$ | --- | 1.7 | --- | Ω |
| Q_g | Total Gate Charge (4.5V) | $V_{DS}=15V, V_{GS}=10V, I_D=15A$ | --- | 56.9 | --- | nC |
| Q_{gs} | Gate-Source Charge | | --- | 13.8 | --- | |
| Q_{gd} | Gate-Drain Charge | | --- | 23.5 | --- | |
| $T_{d(on)}$ | Turn-On Delay Time | $V_{DD}=15V, V_{GS}=10V$ $R_G=3.3\Omega,$ $I_D=1A$ | --- | 20.1 | --- | ns |
| T_r | Rise Time | | --- | 6.3 | --- | |
| $T_{d(off)}$ | Turn-Off Delay Time | | --- | 124.6 | --- | |
| T_f | Fall Time | | --- | 15.8 | --- | |
| C_{iss} | Input Capacitance | $V_{DS}=15V, V_{GS}=0V, f=1\text{MHz}$ | --- | 5850 | --- | pF |
| C_{oss} | Output Capacitance | | --- | 720 | --- | |
| C_{rss} | Reverse Transfer Capacitance | | --- | 525 | --- | |
| I_S | Continuous Source Current ^{1,5} | $V_G=V_D=0V$, Force Current | --- | --- | 205 | A |
| I_{SM} | Pulsed Source Current ^{2,5} | | --- | --- | 500 | A |
| V_{SD} | Diode Forward Voltage ² | $V_{GS}=0V, I_S=1A, T_J=25^\circ\text{C}$ | --- | --- | 1.2 | V |

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{DD}=25V, V_{GS}=10V, L=0.1\text{mH}, I_{AS}=70.2A$
- 4.The power dissipation is limited by 175°C junction temperature
- 5.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.
- 6.Package limitation current is 120A.

Typical Characteristics

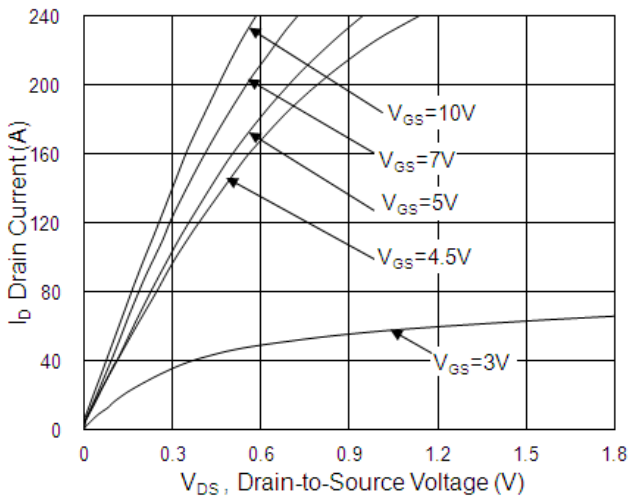


Fig.1 Typical Output Characteristics

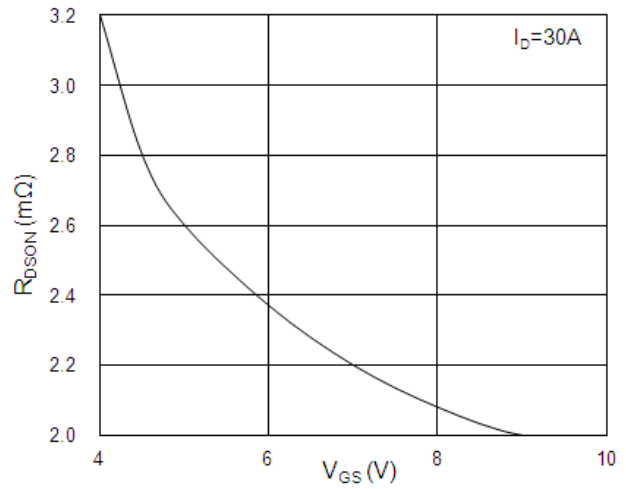


Fig.2 On-Resistance v.s Gate-Source

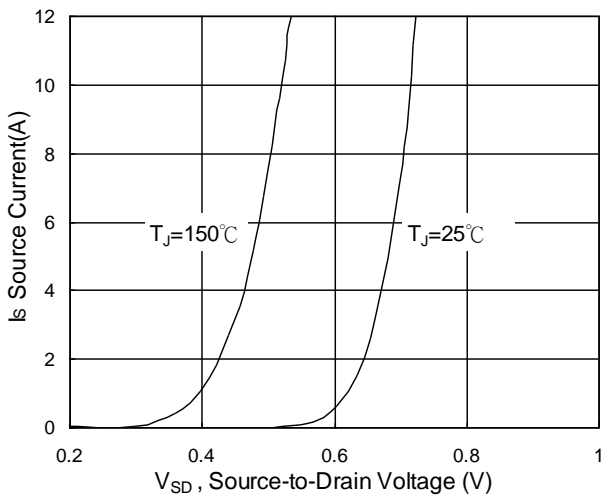


Fig.3 Forward Characteristics of Reverse

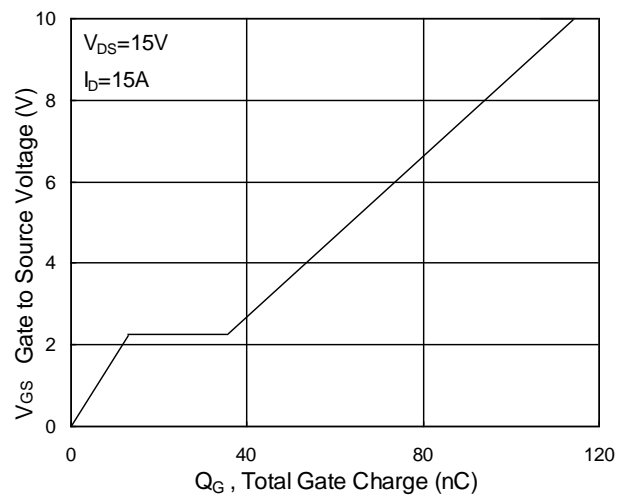


Fig.4 Gate-Charge Characteristics

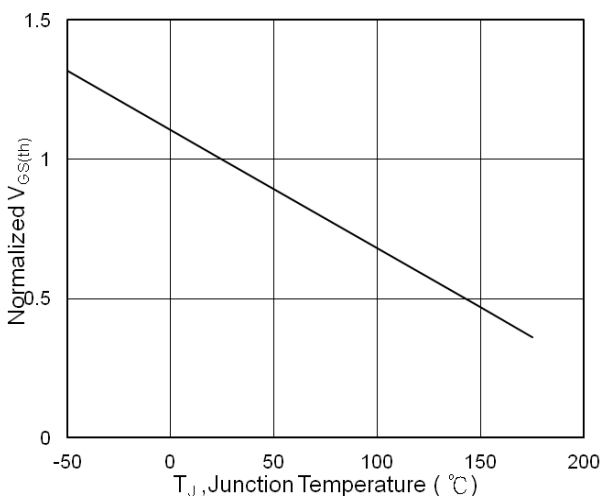


Fig.5 Normalized $V_{GS(th)}$ v.s T_J

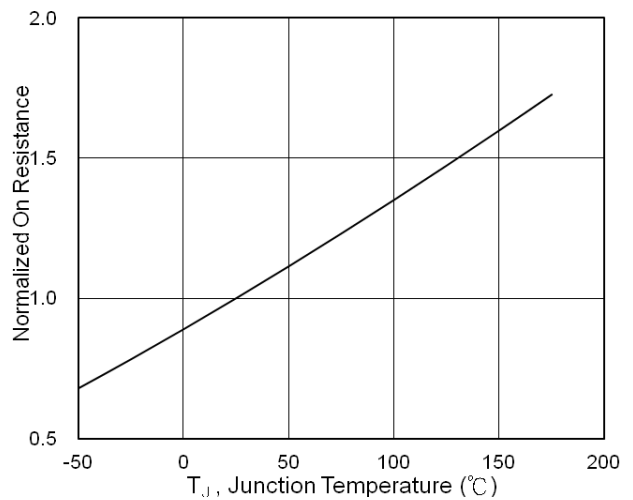


Fig.6 Normalized $R_{DS(on)}$ v.s T_J

30V N-Channel Enhancement Mode MOSFET

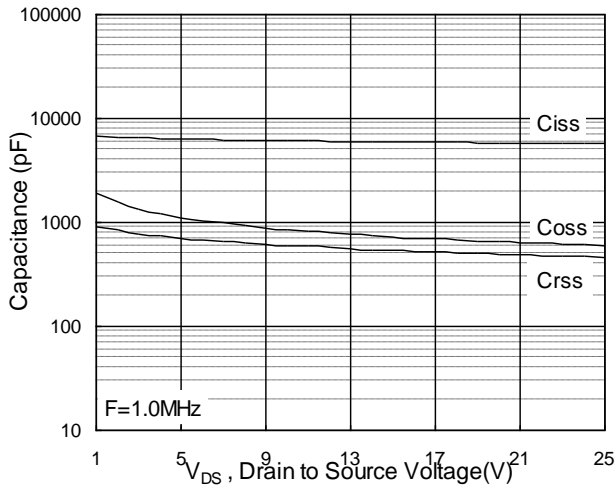


Fig.7 Capacitance

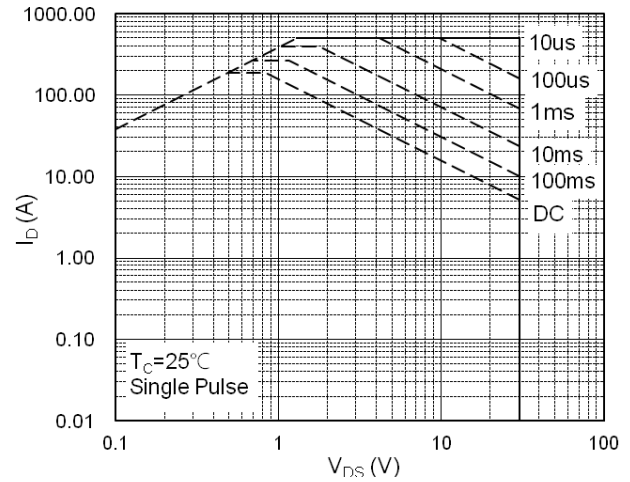


Fig.8 Safe Operating Area

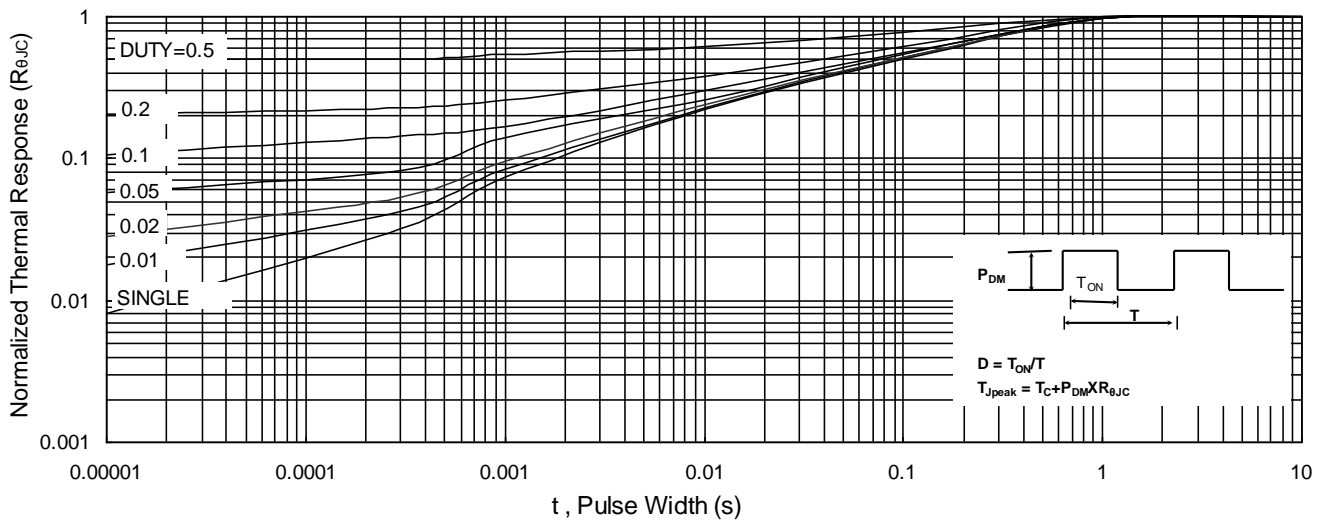


Fig.9 Normalized Maximum Transient Thermal Impedance

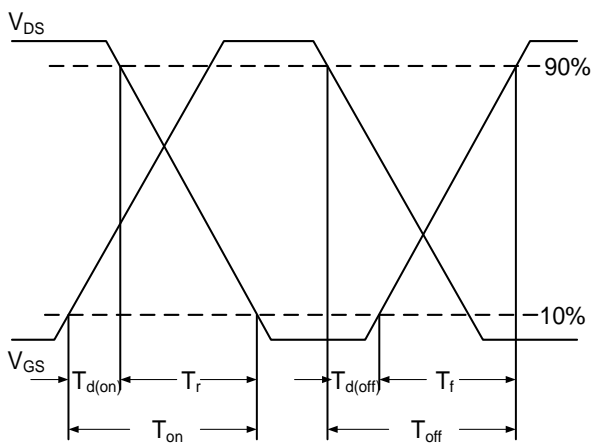


Fig.10 Switching Time Waveform

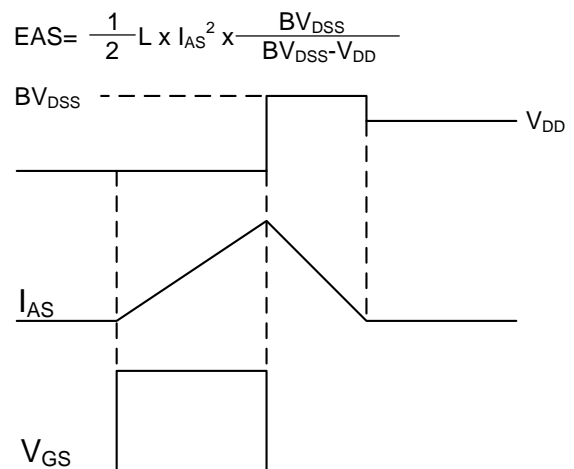
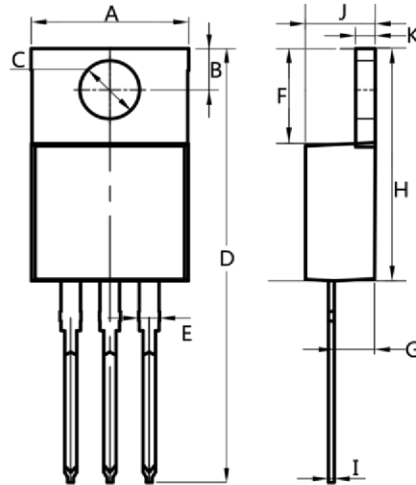


Fig.11 Unclamped Inductive Switching Waveform

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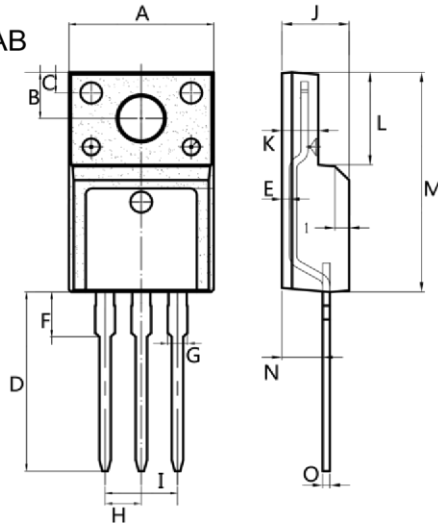
TO-220AB



| Dim. | Min. | Max. |
|------|------|------|
| A | 10.0 | 10.4 |
| B | 2.5 | 3.0 |
| C | 3.5 | 4.0 |
| D | 28.0 | 30.0 |
| E | 1.1 | 1.5 |
| F | 6.2 | 6.6 |
| G | 2.9 | 3.3 |
| H | 15.0 | 16.0 |
| I | 0.35 | 0.45 |
| J | 4.3 | 4.7 |
| K | 1.2 | 1.4 |

All Dimensions in millimeter

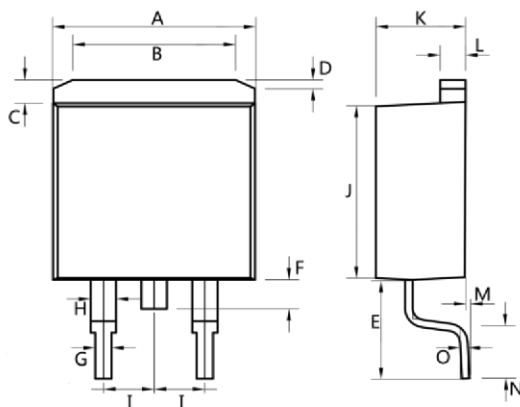
ITO-220AB



| Dim. | Min. | Max. |
|------|----------|-------|
| A | 9.9 | 10.3 |
| B | 2.9 | 3.5 |
| C | 1.15 | 1.45 |
| D | 12.75 | 13.25 |
| E | 0.55 | 0.75 |
| F | 3.1 | 3.5 |
| G | 1.25 | 1.45 |
| H | Typ 2.54 | |
| I | Typ 5.08 | |
| J | 4.55 | 4.75 |
| K | 2.4 | 2.7 |
| L | 6.35 | 6.75 |
| M | 15.0 | 16.0 |
| N | 2.75 | 3.15 |
| O | 0.45 | 0.60 |

All Dimensions in millimeter

TO-263



| Dim. | Min. | Max. |
|------|----------|------|
| A | 10.0 | 10.5 |
| B | 7.25 | 7.75 |
| C | 1.3 | 1.5 |
| D | 0.55 | 0.75 |
| E | 5.0 | 6.0 |
| F | 1.4 | 1.6 |
| G | 0.75 | 0.95 |
| H | 1.15 | 1.35 |
| I | Typ 2.54 | |
| J | 8.4 | 8.6 |
| K | 4.4 | 4.6 |
| L | 1.25 | 1.45 |
| M | 0.02 | 0.1 |
| N | 2.4 | 2.8 |
| O | 0.35 | 0.45 |

All Dimensions in millimeter

30V N-Channel Enhancement Mode MOSFET**Attention**

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